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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/721,488	11/25/2003	Shiping Guo	EMCORE 3.0-081	6052
530	7590 02/13/2006		EXAMINER	
LERNER, DAVID, LITTENBERG,			TRAN, MINH LOAN	
	KRUMHOLZ & MENTLIK 600 SOUTH AVENUE WEST			PAPER NUMBER
WESTFIELD, NJ 07090			2826	
			DATE MAILED: 02/13/200	6

Please find below and/or attached an Office communication concerning this application or proceeding.

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		Application No.	Applicant(s)	
		10/721,488	GUO ET AL.	
Oi	ffice Action Summary	Examiner	Art Unit	
·		Minh-Loan T. Tran	2826	
<i> The</i> Period for Rep		ation appears on the cover sheet wit	h the correspondence address	
WHICHEVE - Extensions of after SIX (6) N - If NO period for Failure to repl Any reply received.	ER IS LONGER, FROM THE MA time may be available under the provisions of MONTHS from the mailing date of this commu or reply is specified above, the maximum statu y within the set or extended period for reply w	PR REPLY IS SET TO EXPIRE 3 MC ALING DATE OF THIS COMMUNIC 16 37 CFR 1.136(a). In no event, however, may a renication. utory period will apply and will expire SIX (6) MONT ill, by statute, cause the application to become AB/er the mailing date of this communication, even if ti	ATION. ply be timely filed HS from the mailing date of this communication ANDONED (35 U.S.C. § 133).	
Status				
1)⊠ Resp	onsive to communication(s) filed	on <u>25 November</u> 2005.		
	• • •	o)☐ This action is non-final.		
		or allowance except for formal matte e under <i>Ex parte Quayle</i> , 1935 C.D.	•	s
Disposition of	Claims			
4a) Of 5)⊠ Claim 6)⊠ Claim 7)⊠ Claim	(s) <u>1-33</u> is/are pending in the ap the above claim(s) <u>10-18 and 2</u> (s) <u>1-9</u> is/are allowed. (s) <u>19-21</u> is/are rejected. (s) <u>22-24</u> is/are objected to. (s) are subject to restricti	<u>5-33</u> is/are withdrawn from conside	ation.	
Application Pa	pers pecification is objected to by the	Evaminer		
		a) accepted or b) objected to b	v the Examiner.	
		ion to the drawing(s) be held in abeyand		
		he correction is required if the drawing(s	• •	d).
11)☐ The oa	ath or declaration is objected to I	by the Examiner. Note the attached	Office Action or form PTO-152.	
Priority under	35 U.S.C. § 119			
12)	wledgment is made of a claim for b) Some * c) None of: Certified copies of the priority do Certified copies of the priority do Copies of the certified copies of application from the International	ocuments have been received in Ap the priority documents have been r	plication No eceived in this National Stage	
Attachment(s)	erences Cited (PTO-892)	4) 🗆 Intensious Su	mman/ (PTO 412)	
2) 🔲 Notice of Dra	ftsperson's Patent Drawing Review (PT0 lisclosure Statement(s) (PT0-1449 or P	O-948) Paper No(s)	mmary (PTO-413) /Mail Date ormal Patent Application (PTO-152) 	

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DETAILED ACTION

Specification

1. The title of the invention is not descriptive. A new title is required that is clearly indicative of the invention to which the claims are directed.

Claim Rejections - 35 USC § 112

2. The following is a quotation of the second paragraph of 35 U.S.C. 112:

The specification shall conclude with one or more claims particularly pointing out and distinctly claiming the subject matter which the applicant regards as his invention.

Claim 20 is rejected under 35 U.S.C. 112, second paragraph, as being indefinite for failing to particularly point out and distinctly claim the subject matter which applicant regards as the invention.

In claim 20, lines 3 and 4, "said first superlattice consist essentially of semiconductors according to the formula Al_rGa _(1-r)N, where **0** ✓ **4** " is inconsistent with claim 19 because claim 19 recites 0<r<1.

Claim Rejections - 35 USC § 103

- 3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 19 and 20 are rejected under 35 U.S.C. 103(a) as being unpatentable over Weeks, Jr. et al. (6,617060).

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Figures 3A, 3B, 6-8 of Weeks, Jr. et al. disclose a semiconductor structure comprising a silicon substrate 14; an AlN nucleation layer 28 (fig. 6) overlying a surface of the silicon substrate 14; a buffer structure 12 including a superlattice structure directly overlying the AlN nucleation layer 28, the superlattice including a plurality of nitride-based semiconductors of different compositions, wherein each of the plurality of nitride-based semiconductors having its respective composition according to the formula Al_xGa (1-x)N, where 0<x<1 and In concentration is equal to 0 (see lines 41-65 in column 5, claims 14 and 15 of Weeks, Jr. et al.), an operative structure of one or more GaN-based semiconductors (16-36) overlying the buffer structure 12 (fig. 7, 8).

Weeks, Jr. et al. does not disclose the nucleation layer 28 having a polycrystalline structure. However, it would have been obvious to one of ordinary skill in the art to form the AlN nucleation layer 28 of Weeks, Jr. et al. having polycrystalline structure because such crystalline structure of AlN is conventional in the art for forming the buffer layer for reducing the lattice mismatch between the silicon substrate and the GaN-based semiconductor structure overlying the silicon substrate.

Claim 21 is rejected under 35 U.S.C. 103(a) as being unpatentable over Weeks, Jr. et al. (6,617060) in view of Feltin et al. (Stress control in GaN grown on silicon (111) by metalorganic vapor phase epitaxy, Applied Physics Letters, Vol. 79, No. 20, Nov. 2001.)

Figures 3A, 3B, 6-8 of Weeks, Jr. et al. disclose all the subject matter claimed except for the second superlattice including a plurality of nitride-based semiconductors

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overlying an intermediate layer. However, figure 1 of Feltin et al. discloses a first superlattice including a plurality of nitride-based semiconductors, a GaN intermediate layer overlying the first superlattice and a second superlattice including plurality of nitride-based semiconductors overlying the GaN intermediate layer.

Therefore, it would have been obvious to one of ordinary skill in the art to form the buffer structure of Weeks, Jr. et al. having a second superlattice including a plurality of nitride-based semiconductors overlying an intermediate layer such as taught by Feltin et al. in order to decrease the stress, thus preventing crack formation in an overgrown GaN-based semiconductors.

Allowable Subject Matter

4. Claims 1-9 are allowed.

Claims 1-9 are allowed over the prior art of record because none of these references disclose or can be combined to yield the claimed invention such as a layer of aluminum directly formed on the surface of the silicon substrate and the polycrystalline nucleation layer of nitride semiconductor directly overlying the aluminum layer as recited in claim 1.

5. Claims 22-24 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

Response to Arguments

6. Applicant's arguments with respect to claims 1-9 and 19-24 have been considered but are most in view of the new ground(s) of rejection.

Conclusion

7. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

8. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Minh-Loan T. Tran whose telephone number is (571) 272-1922. The examiner can normally be reached on Monday-Friday 9:00 AM-5:30 PM.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nathan J. Flynn can be reached on (571) 272-1915. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Mlt 02/2006 Minh-Loan T. Tran Primary Examiner Art Unit 2826

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